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Table of Contents

Table of Contents	iii
Message from the General Chairman.....	xiv
Message from the Technical Program Chair	xv
IEEE AUTOTESTCON 2015 Committee	xvi
IEEE AUTOTESTCON 2015 Sponsors	xvii
IEEE AUTOTESTCON 2015 Promotional Partners	xviii
Awards	xx
Featured Speakers	xxi
Tutorials Program.....	xxii
Master Schedule	xxvii
Tutorials Program Schedule	xxviii
Technical Program Schedule.....	xxix
IEEE AUTOTESTCON 2016 Call for Papers	xxx

Tuesday, 3 November, 2015

1A4: ATE Lessons Learned

3:00 PM - 4:30 PM

Session Chair: Joe Cuccaro (US Army, USA)

Utilizing the SETR Process in the Procurement of TPSs on the CASS Family of Testers 1

Bill Heyn (Fleet Readiness Center SE, USA)

Bob Shilling (Fleet Readiness Center SE, USA)

Test Program and ATE Station Dependencies: Have we learned anything from the past, or are we doomed to repeat it? 9

Michael Seavey (Northrop Grumman Corporation, USA)

Dale Reitze (Northrop Grumman Corporation, USA)

It's Just STE: Understanding the pitfalls of treating STE as second class equipment 12

David C. Holmes (Raytheon Company, USA)

Designing Factory Support Equipment for Field Use 15

Christopher Phillips (Northrop Grumman Technical Services, USA)

Jesse Sandoval (Northrop Grumman Technical Services, USA)

Todd Burton (Northrop Grumman Technical Services, USA)

Derrick Jensen (Northrop Grumman Technical Services, USA)

1B4: New Concepts in Managing Support Infrastructures

3:00 PM - 4:30 PM

Session Chair: Samuel Winters (NAVAIR, USA)

Predicting Field Performance of On-Board Diagnostics using Statistical Methods 19

David Hetherington (Asatte Press, Inc, USA)

High Speed Shared Memory Networks in Hardware in the Loop Applications 27

Troy Troshynski (Avionics Interface Technologies, USA)

Hardware-Based Whitelisting for Automated Test System Cybersecurity and Configuration Management 33

Christopher Geiger (Lockheed Martin Mission Systems and Training, USA)

Robert Hale (Lockheed Martin Enterprise Operations, USA)

Mathew VanDerPol (Lockheed Martin Information Systems & Global Solutions, USA)

Kyle Borowski (Lockheed Martin Information Systems & Global Solutions, USA)

Performance Based Logistics Sustainment of Automated Test Equipment Systems 38

Geoffrey C Casner (Lockheed Martin MST, USA)

Harley J Bieber (Lockheed Martin MST, USA)

1C4: Design for Test/BIT 1

3:00 PM - 4:30 PM

Session Chair: Louis Ungar (Advanced Test Engineering (A.T.E.) Solutions, Inc., USA)

Mitigating the Impact of False Alarms and No Fault Found Events in Military Systems 45

Mustafa Ilarslan (Turkish Air Forces, Turkey)

Louis Y. Ungar (A.T.E. Solutions, Inc., USA)

Processor Controlled Test Development: A Case Study with an Intel i7 Processor Board 47

Nur Baki Er (ASELSAN Inc., Turkey)

Ali Aydoğan (ASELSAN Inc., Turkey)

Hayrettin Kesim (ASELSAN Inc., Turkey)

Wrapper Scan Chains Balance Algorithm Base on Twice Assigned by Difference and Mean Value 52

Deng Libao (Harbin Institute of Technology at Weihai, P.R. China)

Fu Ning (Harbin Institute of Technology, P.R. China)

Qiao Liyan (Harbin Institute of Technology, P.R. China)

Developing Built In Test to Meet The Demands of the Product Test Lifecycle 58

Stacy Gottesman (Raytheon Missile Systems, USA)

Juan Ramos (Raytheon Missile Systems, USA)

James Valfre (Raytheon Missile Systems, USA)

1D4: Managing Obsolescence

3:00 PM - 4:30 PM

Session Chair: Lyle Beck (NAVAIR, USA)

Strategies for Extending the Life of ATE Systems for Another 10 or 20 years 65

Duane Lowenstein (Keysight Technologies, USA)

Joe LaGrotta (Keysight Technologies, USA)

Supporting a product's life cycle utilizing reusable ATML compliant test documentation 71

Mukund Modi (NAVAIR, USA)

Joseph J Stanco (TPS Associates, Inc., USA)

Patrick Verbovsky (NAVAIR, USA)

**Human-Machine Interface: A Framework for Contingency Management
of Complex Aerospace Systems 80**

Jiaming Li (Georgia Institute of Technology, USA)

George Vachtsevanos (Georgia Institute of Technology, USA)

Proactively Managing Obsolescence With Test System Architecture 87

Benjamin Robinson (National Instruments Incorporated, USA)

Bradley Hughes (National Instruments Incorporated, USA)

Robert Bauer (National Instruments Incorporated, USA)

Jake Harnack (National Instruments Incorporated, USA)

Wednesday, November 4, 2015

2A2: ATE Software

10:00 AM - 11:30 AM

Session Chair: Peter L. Hansen (Teradyne, Inc., USA)

Multiple Test Executives in ATE 93

William J Headrick (Lockheed Martin Mission Systems and Training, USA)

An Ideal TPS Relational Analysis 97

Jason J Bell (NAVAIR Jacksonville, FL, USA)

Gilberto García (NAVAIR Jacksonville, FL, USA)

Software Plug-ins for Flexible Test Cell Automation 103

Nathan D. Forster (Southwest Research Institute, USA)

Walter D. Downing (Southwest Research Institute, USA)

An Adaptive Real-time Outlier Detection Algorithm Based on ARMA Model for Radar's Health Monitoring..... 108

Yongle Lv (Nanjing Research Institute of Electronics Technology, P.R. China)

2B2: Improving Accuracy and Reliability of Test Results

10:00 AM - 11:30 AM

Session Chair: Dean Matsuura (Teradyne Inc., USA)

Understanding Optimal Performance of Electronic Circuitry..... 115

Larry V. Kirkland (WesTest Engineering Corp., USA)

Cumulant Statistical Adaptation of Non-linear Post Conversion Correction for TI-ADCs..... 121

Charna R. Parkey (University of Central Florida, USA)

Wasfy B. Mikhael (University of Central Florida, USA)

Implementation of System Testing Automatization on Computer Aided Systems for Hardware and Software 127

Alper Avcioglu (Aselsan Inc., Turkey)

Mehmet Demirer (Hacettepe University, Turkey)

Detection of Soft Errors through Checksums in Redundant Execution Systems 134

Luis Bustamante (University of California, USA)

Hussain Al-Asaad (University of California, USA)

2C2: Prognostics and Health Monitoring 1

10:00 AM - 11:30 AM

Session Chair: Robert R. Fox (US Navy, USA)

Battery Health Degradation and Optimal Life Management 138

A. Abdollahi (University of Connecticut, USA)

N. Raghunathan (University of Connecticut, USA)

X. Han (University of Connecticut, USA)

B. Pattipati (University of Connecticut, USA)

B. Balasingam (University of Connecticut, USA)

K. R. Pattipati (University of Connecticut, USA)

Y. Bar-Shalom (University of Connecticut, USA)

B. Card (Fairchild Semiconductor Corp., USA)

Prediction of Wireless Sensor Battery life	146
<i>SB Mahalakshmi (GE - Global Research, India)</i>	
<i>Senthil Datchanamoorthy (GE - Global Research, India)</i>	
Deriving Prognostic Continuous Time Bayesian Networks from D-matrices	152
<i>Logan Perreault (Montana State University, USA)</i>	
<i>Monica Thornton (Montana State University, USA)</i>	
<i>Shane Strasser (Montana State University, USA)</i>	
<i>John W. Sheppard (Montana State University, USA)</i>	
A Battery Certification Testbed for Small Satellite Missions	162
<i>Zachary Cameron (Pennsylvania State University, USA)</i>	
<i>Chetan S. Kulkarni (NASA Ames Research Center, USA)</i>	
<i>Ali Guarneros Luna (NASA Ames Research Center, USA)</i>	
<i>Kai Goebel (NASA Ames Research Center, USA)</i>	
<i>Scott Poll (NASA Ames Research Center, USA)</i>	
2A3: Specialty ATE	
1:30 PM - 3:00 PM	
Session Chair: Chetan Kulkarni (SGT, NASA Ames Research Center & NASA Ames Research Center, USA)	
Developing Easy Pluggable Test Equipments for Factory and Development Testing of Air Defense Gun System	169
<i>Onur Yaşar (ASELSAN INC., Turkey)</i>	
<i>Hakan Caner (ASELSAN INC., Turkey)</i>	
Spectroscopic Electromagnetic Analysis Approach to Non-Contact Circuit Board Test and Diagnosis	173
<i>R. Glenn Wright (GMA Industries, Inc., USA)</i>	
Modular Automatic Test Equipment Design for On-Platform Diagnostics	181
<i>Ryan Nielsen (United States Army, ARDEC, USA)</i>	
<i>Daniel A. Tagliente (United States Army, ARDEC, USA)</i>	
2B3: Software Testing	
1:30 PM - 3:00 PM	
Session Chair: Larry Attkisson (Northrop Grumman, USA)	
The Quality of Your Code is the Quality of Your Brand - and it's Time to Pay Attention to Software Testing	186
<i>John Paliotta (Vector Software, USA)</i>	
The Next Step in Verification Testing of Complex Systems is Automation	194
<i>Edward Dou (Raytheon Company, USA)</i>	
<i>Christian Reascos (Raytheon Company, USA)</i>	
Manual Testing's Newfound Place in the Automated Testing World	199
<i>G. Philip Rogers (NPR Digital Media, USA)</i>	
<i>Paul Miles (NPR Digital Media, USA)</i>	
Practical Methods for Automatic MC/DC Test Case Generation of Boolean Expressions	203
<i>Sekou Kangoye (Valeo Comfort and Driving Assistance, France)</i>	
<i>Alexis Todoskoff (University of Angers/LARIS, France)</i>	
<i>Mihaela Barraeu (University of Angers/LARIS, France)</i>	

2C3: Prognostics and Health Monitoring 2

1:30 PM - 3:00 PM

Session Chair: John W. Sheppard (Montana State University, USA)

UAV equipment modeling and fault analysis..... N/A

Deng Dawei (Beihang University, P.R. China)

Yuan Haiwen (Beihang University, P.R. China)

Fault Propagation Characteristics Analysis for Large-scale Electronic System by Hierarchical Signed Directed Graph..... 219

Zhiming Yang (Harbin Institute of Technology, P.R. China)

Chengcheng Zhang (Harbin Institute of Technology, P.R. China)

Min Zhuang Liu (Harbin Institute of Technology, P.R. China)

Yang Yu (Harbin Institute of Technology, P.R. China)

Liyang Qiao (Harbin Institute of Technology, P.R. China)

Xiyuan Peng (Harbin Institute of Technology, P.R. China)

Faults Detection and Failures Prediction Using Vibration Analysis 227

Tristan Plante (University of North Dakota, USA)

Ashkan Nejadpak (University of North Dakota, USA)

Cai Xia Yang (University of North Dakota, USA)

Flexible High Performance Architecture For Boundary Scan Execution Hardware 232

Terry Borroz (Teradyne, Inc., USA)

2A4: Technology Insertion in Today's Instrumentation

3:30 PM - 5:00 PM

Session Chair: James Lytle (NAVAIR, USA)

An Automated, Low Complex End To End Resistance Measurement System For Multi-Channel Slip-Rings..... 236

Ahmet Karakaya (ASELSAN Inc., Turkey)

Muharrem Tümçakır (ASELSAN Inc., Turkey)

The Future of Component Level Miniature and Microminiature Electronic Repair 240

Aaron Caplan (PACE Worldwide, USA)

Cost Effective V&V for Guidance Systems using Enhanced Ground Testing (EGT) 244

Keith Collins (Draper Laboratory, USA)

Brad Goossens (Draper Laboratory, USA)

Daniel Monopoli (Draper Laboratory, USA)

Realization of Controlling eMMC 5.0 Device Based on FPGA for Automatic Test System 251

Ning Fu (Harbin Institute of Technology, P.R. China)

Yuanheng Li (Harbin Institute of Technology, P.R. China)

Baowen Liu (Harbin Institute of Technology, P.R. China)

Hongwei Xu (Harbin Institute of Technology, P.R. China)

Yigang Zhang (Harbin Institute of Technology, P.R. China)

2B4: Novel Test & Diagnostic Techniques 1

3:30 PM - 5:00 PM

Session Chair: Alberto Tungcab (NAVAIR, USA)

The Use of IEEE Standards to Develop Test Program Sets to Support In-Service Legacy Equipment..... 256

Steven Kelly (Ministry Of Defence, U.K.)

Non-integrated Algorithm based on EDA and Tabu Search for Test Task Scheduling Problem 261

Hui Lu (Beihang University, P.R. China)

Mengmeng Zhang (Beihang University, P.R. China)

Automated Continuity Testing of Flexible Backplanes Using a Cable Tester..... 269

Hayrettin Kesim (ASELSAN Inc, Turkey)

Advanced Diagnostics and Anomaly Detection for Railroad Safety Applications: Using a Wireless, IoT-Enabled Measurement System 273

Douglas L. Goodman (Ridgetop Group, Inc., USA)

James Hofmeister (Ridgetop Group, Inc., USA)

Robert Wagoner (Ridgetop Group, Inc., USA)

2C4: FPGA Applications in Modern Instrumentation

3:30 PM - 5:00 PM

Session Chair: Teresa P. Lopes (Teradyne, Inc., USA)

Research on Reconfiguration Technology Based on SOPC for PXI Instrument..... 280

Zhao Guangquan (Harbin Institute of Technology, P.R. China)

Hou Yandong (Harbin Institute of Technology, P.R. China)

Wang Shaojun (Harbin Institute of Technology, P.R. China)

Embedded Synthetic Instruments for O-Level Test: Modular IO and FPGA Technology Provide Increased Flexibility and Decreased Cost of Test..... 284

Robert Bauer (National Instruments, USA)

Reducing the Cost of Test for High-Speed Serial Buses with COTS FPGA Technology..... 288

Chris Nunn (National Instruments, USA)

Incorporation of Field Programmable Gate Array Based Instrumentation into Automated Test Equipment Paper not available

Richard Craig (The Boeing Company, USA)

Thursday, November 5, 2015

3A1: Design for Test/BIT 2

8:30 AM - 10:00 AM

Session Chair: Craig D. Stoldt (BAE Systems, USA)

A Heuristic Approach to Achieving a BIT False Alarm Rate..... 291

Juan Ramos (Raytheon Missile Systems, USA)

Stacy Gottesman (Raytheon Missile Systems, USA)

Phillip Phelps (Raytheon Missile Systems, USA)

Edward Ly (Raytheon Missile Systems, USA)

Identifying Testable and Supportable Commercial-off-the-shelf (COTS) Equipment 301

Louis Y. Ungar (Advanced Test Engineering (A.T.E.) Solutions, Inc., USA)

A Robust CORBA To LabVIEW Solution..... 309

Chris Dulaney (Raytheon, USA)

Sean Beatrice (Raytheon, USA)

Empowering Test Engineering 316

Louis Y. Ungar (Advanced Test Engineering (A.T.E.) Solutions, Inc., USA)

3B1: Novel Test & Diagnostic Techniques 2

8:30 AM - 10:00 AM

Session Chair: Jeff Murrill (Northrop Grumman, USA)

Autonomous Decentralized Test System to Enhance ATS's Survival Probability and Online Maintainability 324

Zhao Xin (Air Force Engineering University, P.R. China)

Xiao Mingqing (Air Force Engineering University, P.R. China)

An Automated Framework for Testing MUOS Voice Calls..... 329

Sunil Ramlall (SPAWAR Systems Center Pacific, USA)

Characterization and Calibration Techniques for Multi-Channel Phase-Coherent Systems 334

Shivansh Chaudhary (National Instruments, USA)

Abhay Samant (National Instruments, USA)

An Efficient Technique Based on DORT Method to Locate Multiple Soft Faults in Wiring Networks 339

Moussa Kafal (Université Pierre et Marie Curie, France)

Andrea Cozza (Université Pierre et Marie Curie, France)

Lionel Pichon (Université Pierre et Marie Curie, France)

3C1: Supportability Enhancement Topics

8:30 AM - 10:00 AM

Session Chair: David Johnson (US Army, USA)

Power Law Behavior in Navy and Marine Corps Avionics Systems 345

Russell Shannon (Naval Air Systems Command, USA)

Maria Legato (Naval Air Systems Command, USA)

Steven Stockhamer (Naval Air Systems Command, USA)

Crystal Wagner (Naval Air Systems Command, USA)

ATE Instrument Function Tracking	350
<i>William J Headrick (Lockheed Martin Mission Systems and Training, USA)</i>	
<i>David Wong (Lockheed Martin Mission Systems and Training, USA)</i>	
Considerations for Testing and Simulation of MIL-STD-1760E/HS1760 Avionics Interfaces	354
<i>Troy Troshynski (Avionics Interface Technologies, USA)</i>	
Aircraft Support Equipment Technology Insertion Plan Improves Aircraft Availability	359
<i>Christopher J. Guerra (Southwest Research Institute, USA)</i>	
<i>Christopher E. Camargo (Southwest Research Institute, USA)</i>	
<i>Jordan T. Nielson (Southwest Research Institute, USA)</i>	
3D1: ATE Development Approaches	
8:30 AM - 10:00 AM	
Session Chair: Dan Christenson (United States Air Force & 748 SCMG/EN, USA)	
Developing Enhanced Light Imaging Test Equipment for DUTS Obsolescence.....	363
<i>Erwin Ho (Boeing, USA)</i>	
ATE Design And Development For I-Level Maintenance And Production Line Of RCIED Jammer Systems	367
<i>Orkun Alp (ASELSAN Inc., Turkey)</i>	
<i>Özden Erdem Kiliç (ASELSAN Inc., Turkey)</i>	
<i>Ali Ayvalik (ASELSAN Inc., Turkey)</i>	
<i>Zafer Savaş (ASELSAN Inc., Turkey)</i>	
Developing a Combined Armament Tester Proof of Concept and Lessons Learned	374
<i>Daniel Zajac (Southwest Research Institute (SwRI), USA)</i>	
<i>Norman Carmichael (Southwest Research Institute (SwRI), USA)</i>	
Common BIT Test Station Agile Development Approach.....	380
<i>W. Tod Newman (Raytheon Missile Systems, USA)</i>	
<i>Gerald Emmert (Raytheon Missile Systems, USA)</i>	
3A2: Design for Test/BIT 3	
10:15 AM - 11:45 AM	
Session Chair: Russell A. Shannon (NAVAIR, USA)	
Improving the Design and Reliability of Future Computer Systems via Using Intermediate Values of Outputs	385
<i>Hussain Al-Asaad (University of California, USA)</i>	
<i>Luis Bustamante (University of California, USA)</i>	
Design of Fault-Tolerant Control Functions for a Primary Flight Control System with Electromechanical Actuators	393
<i>David Arriola (Hamburg University of Technology, Germany)</i>	
<i>Frank Thielecke (Hamburg University of Technology, Germany)</i>	
Development, Integration, and Test Architecture for a Software-Based Hardware-Agnostic Fault Tolerant Flight Computer	403
<i>Andrew Cunningham (The Charles Stark Draper Laboratory, Inc., USA)</i>	
<i>Michael Kass (The Charles Stark Draper Laboratory, Inc., USA)</i>	

3B2: Novel Test & Diagnostic Techniques 3

10:15 AM - 11:45 AM

Session Chair: Christopher J. Sparr (NAVAIR, USA)

Developing a Test Assessment Strategy for Measurement Systems 409

Michael Buckmaster (Astronics AES, USA)

ITA or ITEA: A Comprehensive Dissimilarity 415

Larry V. Kirkland (WesTest Engineering Corp., USA)

Wayne Tjoland (OO-ALC/309th Software Maintenance Group, USA)

UAV flight safety ground test and evaluation 422

Dawei Deng (Beihang University of Aeronautics, P.R. China)

Haiwen Yuan (Beihang University of Aeronautics, P.R. China)

Recommended Practice for the Design and Integration of Fixtures

Applied to Generic Test Interfaces of ATS, IEEE-P1514™ N/A

Michael Stora (SIT, USA)

Rob Spinner (ATTI, USA)

Steve Mann (BCO, Inc., USA)

George Isabella (BAE Systems, USA)

David Droste (CGI, USA)

3C2: TPS Development Solutions

10:15 AM - 11:45 AM

Chair: Michael Seavey (Northrop Grumman, USA)

Unlocking the Buried Margins Entrenched in Test Data 433

Larry V. Kirkland (WesTest Engineering Corp., USA)

A USB-based Automatic Test Equipment with Improved Behavior-based

Automatic Test generation for Complex Circuit Boards 440

Huxun Chen (Beijing, HeroTec Test & Control Ltd., P.R. China)

DeQing Chen (Beijing, HeroTec Test & Control Ltd., P.R. China)

Lei Gao (Beijing, HeroTec Test & Control Ltd., P.R. China)

Jinlin Ye (Beijing, HeroTec Test & Control Ltd., P.R. China)

Weizhou Cao (Beijing, HeroTec Test & Control Ltd., P.R. China)

Kai Liu (Beijing, HeroTec Test & Control Ltd., P.R. China)

Using .NET Remoting In Test Software 446

Çağrı Keleş (Aselsan Inc., Turkey)

Esra Nurgün (Aselsan Inc., Turkey)

Deploying an Enterprise-Class Software Lifecycle Management Solution

for Test Program Sets 450

Timothy W. Davis (TPS Acquisition and SSA Branch, USA)

Gary S. Kane (TPS Acquisition and SSA Branch, USA)

3D2: New Directions in Instrumentation Architectures

10:15 AM - 11:45 AM

Chair: Mark Elo (Giga-tronics Inc., USA)

Shelf Management for AXIe applications 456

Gary Hanson (Elma Electronic, USA)

Mihai Savu (Samway Electronic, USA)

Introducing PXI Instrumentation Into an Existing VXI Based Tester 462
Kevin Paton (Teradyne, Inc., USA)

Multi-channel Phase Coherent Measurements using COTS Modular Instruments..... 468
Alexander Dickson (Keysight Technologies, Inc., USA)

PXI-Based, High Performance, High Density Switching Architecture 478
David Manor (Marvin Test Solutions, USA)
Michael Dewey (Marvin Test Solutions, USA)

AUTHOR INDEX 483